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Paper No. 4

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**DEC 04 2001**

**OFFICE OF PETITIONS**

In re Application of  
Eric Yang et al.  
Application No. 09/854,330  
Filed: May 11, 2001  
For: Contract Management System

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:  
: DECISION GRANTING  
: PETITION  
:

This is a decision on the paper styled "Petition To Correct Filing Receipt" filed July 27, 2001, requesting that the above-identified application be accorded a filing date of May 11, 2001, rather than the presently accorded filing date of May 14, 2001. The request is properly being treated as a petition under 37 CFR 1.10(c).

Petitioner alleges that the application was filed on May 11, 2001. In support of the petition, petitioner has provided a copy of an "Express Mail" mailing label bearing "Express Mail" label no. EL624353193US, the same "Express Mail" label number which appears on the original application transmittal letter. Petitioner requests that the application be accorded a filing date of May 11, 2001.

The Office considers the date the paper or fee is shown to have been deposited as "Express Mail" to be the "Date In" on the Express Mail label; MPEP 513. That is the date that verifies that the package was actually mailed. In view of the above, the evidence is convincing that the application was deposited as "Express Mail" with the US Postal Service on May 11, 2001.

The petition is granted.

The application is being forwarded to the Office of Initial Patent Examination for issuance of a Corrected Filing Receipt.

Telephone inquiries concerning this matter may be directed to Latrice Bond at (703) 308-6911.

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